## Applicant(s)/Patent Under Application/Control No. Reexamination 09/652,159 LIU ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Vanel Frenel 3627 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2005/0261986 11-2005 Haynes et al. 705/026 Α 709/204 US-2002/0013815 01-2002 Obradovich et al. В US-С US-D US-Ε US-F US-G US-Н US-

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

	NON-I ATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

US-

US-

US-

US-

J

Κ

L

М